**Product / Process Change Notice**

**Parts Affected:**

Chip process CP771, P-channel MOSFETs, wafers and bare die.

**Extent of Change:**

The CP771 wafer process has been discontinued and is being replaced with the CP805 wafer process. See Figures 1 and 2 for details.

**Reason for Change:**

The CP771 wafer process has been replaced in order to enhance manufacturing process controls and device performance. This change will help ensure an undisrupted supply of product.

**Effect of Change:**

The CP805 wafer process meets all electrical specifications of the individual devices listed on the following page.

**Qualification:**

|  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- |
|  |  | P/N: | CP805 Chip Process |  | Package: | TO-220 |
|  |  |  |  |  |  |  |
| **No.** | **Test** | **Conditions**(Reference standards are in bold) | **Qty** | **Pass/Fail** | **Test Results** |
| **1** | **Device Life Tests** |
|  | A | **High Temperature Gate Bias (HTGB)** | T=150°C, t = 1000 hours100% V\_GSNegative Bias**JESD22-A108** | 77 | Pass | 77/77 |
|  | B | **High Temperature Gate Bias (HTGB)** | T=150°C, t = 1000 hours100% V\_GSPositive Bias**JESD22-A108** | 77 | Pass | 77/77 |
|  | C | **High Temperature Reverse Bias (HTRB)** | T=150°C, t = 1000 hours100% V\_DS**JESD22-A108** | 77 | Pass | 77/77 |

**Effective Date of Change:**

Existing inventory of chip process CP771 will be shipped until depleted.

**Sample Availability:**

Please contact your salesperson or manufacturer’s representative for samples.

 **Figure 1: CP771 Chip Geometry (Discontinued) Figure 2: CP805 Chip Geometry**

 

Wafer Diameter: 8 inch

Die Size: 55 x 32 mils

Die Thickness: 7.5 mils

Bond Pad Size (Gate): 7.3 x 7.3 mils

Bond Pad Size (Source): 50 x 25 mils

Topside Metal: Al (40,000Å)

Backside Metal: Ti/Ni/Ag (1,000Å/3,000Å/10,000Å)

Wafer Diameter: 8 inch

Die Size: 63.8 X 38.9 mils

Die Thickness: 5.5 mils

Bond Pad Size (Gate): 7.1 x 7.1 mils

Bond Pad Size (Source): 60.4 x 35.6 mils

Topside Metal: Al-Cu (40,000Å)

Backside Metal: Ti/Ni/Ag (1,000Å/3,000Å/10,000Å)

**Part Numbers Affected:**

|  |  |
| --- | --- |
| CXDM4060P | CP771-CXDM4060P-CT |
|  | CP771-CXDM4060P-WN |

As per JEDEC standard JESD46, Customer Notification of Product/Process Changes by Solid-State Suppliers, a lack of acknowledgement of a PCN within thirty (30) days constitutes acceptance of the change.

The undersigned acknowledges and accepts Central Semiconductor’s Product/Process Change Notification (PCN).

|  |  |
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| Company Name: |  |
| Address: |  |
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| Printed Name: |  |
| Title: |  |
| Signature: |  |
| Date: |  |